



TEST REPORT

KCTL Inc.

65, Sinwon-ro, Yeongtong-gu,
Suwon-si, Gyeonggi-do, 16677, Korea
TEL: 82-31-285-0894 FAX: 82-505-299-8311
www.kctl.co.kr

Report No.:

KR22-SRF0014-A

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KCTL

1. Client

- Name : NYX.Inc
- Address : 301, 25, Baemet 2-gil, Naju-si, Jeollanam-do, Republic of Korea
- Date of Receipt : 2021-10-29

2. Use of Report : Certification

3. Name of Product / Model : gosleep / N-GO1-LG-21-KR

4. Manufacturer / Country of Origin : NYX.Inc / Korea

5. FCC ID : 2A395-GOSLEEP

6. Date of Test : 2022-01-10 to 2022-01-18

7. Location of Test : ☒ Permanent Testing Lab ☐ On Site Testing
(Address: 65, Sinwon-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea)

8. Test method used : 47 CRF Part 1.1310

9. Test Result : Refer to the test result in the test report

Affirmation	Tested by	Technical Manager
	Name : Eunseong Lim (Signature)	Name : Heesu Ahn (Signature)

2022-02-21

KCTL Inc.

As a test result of the sample which was submitted from the client, this report does not guarantee the whole product quality. This test report should not be used and copied without a written agreement by KCTL Inc.

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REPORT REVISION HISTORY

Date	Revision	Page No
2022-02-14	Originally issued	-
2022-02-21	Updated	10

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General remarks for test reports

Statement concerning the uncertainty of the measurement systems used for the tests

(may be required by the product standard or client)

☐ Internal procedure used for type testing through which traceability of the measuring uncertainty has been established:

Procedure number, issue date and title:

Calculations leading to the reported values are on file with the testing laboratory that conducted the testing.

☒ Statement not required by the standard or client used for type testing

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1. General information

Client : NYX.Inc
 Address : 301, 25, Baemet 2-gil, Naju-si, Jeollanam-do, Republic of Korea
 Manufacturer : NYX.Inc
 Address : 301, 25, Baemet 2-gil, Naju-si, Jeollanam-do, Republic of Korea
 Laboratory : KCTL Inc.
 Address : 65, Sinwon-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16677, Korea
 Accreditations : FCC Site Designation No: KR0040, FCC Site Registration No: 687132
 VCCI Registration No. : R-20080, G-20078, C-20059, T-20056
 CAB Identifier: KR0040, ISED Number: 8035A
 KOLAS No.: KT231

2. Device information

Equipment under test : gosleep
 Model : N-GO1-LG-21-KR
 Modulation technique : ASK
 Frequency range : 110 kHz ~ 150 kHz
 Power source : DC 12 V
 Antenna specification : Coil Antenna
 Software version : rev.1
 Hardware version : rev.1
 Test device serial No. : N/A
 Operation temperature : -20 °C ~ 50 °C

Note: Cetificated module is mounted in the EUT as following
 - Application ESPRESSIF SYSTEMS (SHANGHAI) CO., LTD
 - Contains FCC ID : 2AC7Z-ESP32WROOM32E
 - Model : ESP32-WROOM-32E

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2.1. Accessory information

Equipment	Manufacturer	Model	Serial No.	FCC ID
Smart Phone	Samsung Electronics Co., Ltd.	SM-G998N	-	-

2.2. Frequency/channel operations

This device contains the following capabilities:

WPT

Frequency (kHz)
110 ~ 150

Table 2.2.1. WPT



3. Measurement uncertainty

The measurement uncertainties shown below were calculated in accordance with the requirements of ANSI C63.10-2013.

All measurement uncertainty values are shown with a coverage factor of $k=2$ to indicated a 95 % level of confidence. The measurement data shown herein meets or exceeds the U_{CISPR} measurement uncertainty values specified in CISPR 16-4-2 and thus, can be compared directly to specified limits to determine compliance.

Parameter	Expanded uncertainty ($\pm$)	
Conducted RF power	1.3 dB	
E-Field	3 kHz ~ 10 MHz	11.04 %
H-Field	3 kHz ~ 10 MHz	13.80 %



4. RF Exposure

4.1. FCC Regulation

This document is prepared to show compliance with the RF Exposure requirements as required in §1.1310 of the FCC rules and Regulations.

The limit for Maximum Permissible Exposure (MPE), specified in FCC §1.1310, is listed in Table 1-1. According to FCC §1.1310: the criteria listed in the following table shall be used to evaluate the environmental impact of human exposure to radio-frequency (RF) radiation as specified in §1.1307(b).

Table 1 – Limits for Maximum Permissible Exposure (MPE)

Frequency Range (MHz)	Electric Field Strength [V/m]	Magnetic Field Strength [A/m]	Power Density [mW/cm ²]	Averaging Time [minute]
(A) Limits for Occupational / Controlled Exposure				
0.3 ~ 3.0	614	1.63	*100	6
3.0 ~ 30	1842/f	4.89/f	*900/f ²	6
30 ~ 300	61.4	0.163	1.0	6
300 ~ 1 500	/	/	f/300	6
1 500 ~ 15 000	/	/	5	6
(B) Limits for General Population / Uncontrolled Exposure				
0.3 ~ 1.34	614	1.63	*100	30
1.34 ~ 30	824/f	2.19/f	*180/f ²	30
30 ~ 300	27.5	0.073	0.2	30
300 ~ 1 500	/	/	f/1 500	30
1 500 ~ 15 000	/	/	1.0	30

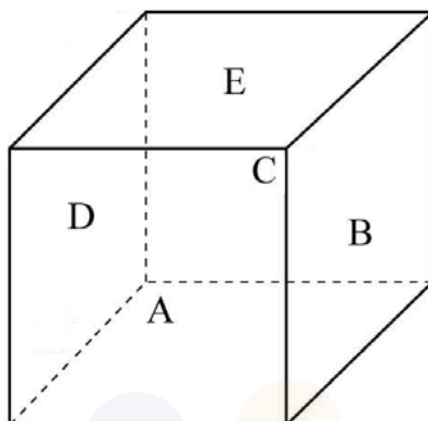
f=frequency in MHz, ***= plane-wave equivalent power density

Per the guidance of KDB 680106, the E-field and H-field limits shown in the table above are extended down to 100 kHz

4.2. Test Set-up

4.2.1. Isotropic Probe test setup

The measurement probe (EHP-200A) is a regular hexahedron and supports 3-axis (X, Y and Z) isotropic probe.



A: Front of measurement probe

B: Right of measurement probe

C: Rear of measurement probe

D: Left of measurement probe

E: Top of measurement probe

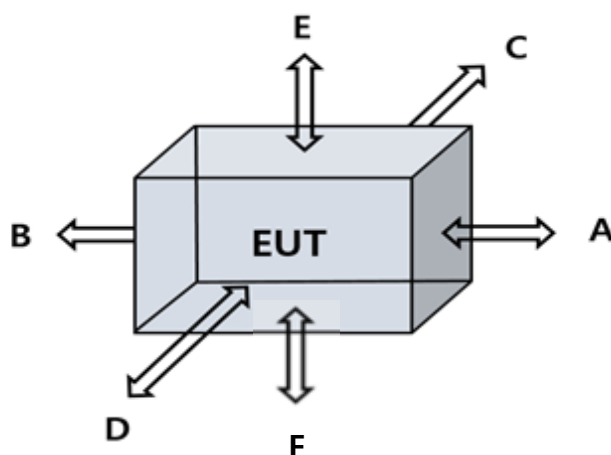
*Bottom of measurement probe is not used to measure RF exposure condition owing to connection with a stick.

At 0 cm distance, measurement isotropic probe was investigated by rotating the probe through various angles for one of the EUT's sides as below.

Measurement Point	A	B	C	D	E
Direction	Front	Right	Rear	Left	Top
Measurement Point	A to B	B to C	C to D	D to A	N/A
Direction	Front to Right	Right to Rear	Rear to Left	Left to Front	-
Measurement Point	A to E	B to E	C to E	D to E	N/A
Direction	Front to Top	Right to Top	Rear to Top	Left to Top	-

When the worst angle among all angles was found, RF exposure measurement should be adjusted from worst angle.

4.2.2. EUT test setup



- 1) Testing was performed with a calibrated field probe.
- 2) Measurement was performed on each side of the EUT as described per below table.

A	B	C	D	E	F
Front	Rear	Right	Left	Top	Bottom

Measurement Probe	EHP-200A (Manufacturer: Narda)
Measurement Method	Direct measurement
Measurement Distance	Surface of the EUT to the center of the probe.

- Support equipment

Equipment	Manufacturer	Model	Serial No.	FCC ID
Smart Phone	Samsung Electronics Co., Ltd.	SM-G950N	-	A3LSM-G950N

Equipment Approval Considerations item 5.b) of KDB 680106 D01 v03

- a) Power transfer frequency is less than 1 MHz.
 - ▶ Normal Charge condition is operates at a frequency of 147 kHz.
 - ▶ Fast Charge condition is operates at a frequency of 118 kHz.
- b) Output power from each primary coil is less than or equal to 15 watts.
 - ▶ Normal Charge condition / Output power from each primary coil : 5 watts.
 - ▶ Fast Charge condition / Output power from each primary coil : 10 watts.
- c) The transfer system includes 3 primary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.
 - ▶ The transfer system includes 3 primary coils.
- d) Client device is placed directly in contact with the transmitter.
 - ▶ The client device is placed directly in contact with the transmitter.
- e) Mobile exposure conditions only (portable exposure conditions are not covered by this exclusion)
 - ▶ This device is mobile exposure condition.
- f) The aggregate H-field strengths at 15cm surrounding the device and 20cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.
 - ▶ The EUT field strength levels < 50 % of the MPE limit 1.63 A/m
 0.086 A/m (Max) < 0.815 A/m

4.3. Test configuration (Description of test mode)

Test case configuration is reported as below.

Test Mode	Description
TM1	EUT + Mobile phone(Battery status: < 10%)
TM2	EUT + Mobile phone(Battery status: < 50%)
TM3	EUT + Mobile phone(Battery status: > 90%)

4.4. Test result

- Normal Charge mode

4.4.1. Test mode: test result of rotating the probe through various angles

Distance : 15_{cm} surrounding the device and 20_{cm} above the top surface.

- E-field measurement results (Sides of probe)

Frequency [MHz]	E-field Measurement [V/m]					Limits [V/m]
	Probe rotation					
	A	B	C	D	E	
0.147	1.466 0	2.057 8	1.909 8	1.326 7	1.650 6	614.00

- H-field measurement results (Sides of probe)

H-field measurement results (Sides of probe)						
Frequency [MHz]	H-field Measurement [A/m]					Limits [A/m]
	Probe rotation					
	A	B	C	D	E	
0.147	0.076 3	0.049 4	0.056 9	0.055 4	0.056 6	1.630

- E-field measurement results (Rotation of probe)

E-field measurement results (Rotation of probe)									
Frequency [MHz]	E-field Measurement [V/m]								Limits [V/m]
	Probe rotation								
	A to E	B to E	C to E	D to E	A to B	B to C	C to D	D to A	
0.147	0.061 0	0.051 9	0.053 5	0.044 1	1.376 8	1.563 9	1.319 4	1.253 5	614.00

- H-field measurement results (Rotation of probe)

H-field measurement results (Rotation of probe)									
Frequency [MHz]	H-field Measurement [A/m]								Limits [A/m]
	Probe rotation								
	A to E	B to E	C to E	D to E	A to B	B to C	C to D	D to A	
0.147	0.061 0	0.051 9	0.053 5	0.044 1	0.047 5	0.039 8	0.071 6	0.072 6	1.630

Note:

- Worst Case: E-field = B-side, H-field = A-side.

4.4.2. Test mode: Test result of EUT's sides about the distance

Distance : 15cm surrounding the device and 20cm above the top surface.

- E-field measurement results

Test Mode	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
TM1	0.147	0.235 2	0.222 0	0.231 3	0.218 7	1.333 4	0.218 4	614.00
TM2	0.147	0.236 5	0.223 3	0.230 2	0.225 1	1.329 3	0.222 2	
TM3	0.147	0.231 2	0.220 3	0.229 2	0.223 5	1.192 7	0.217 3	

- H-field measurement results

Test Mode	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
TM1	0.147	0.086 1	0.080 1	0.076 5	0.054 1	0.132 1	0.082 5	0.814
TM2	0.147	0.074 5	0.070 5	0.072 7	0.062 4	0.131 1	0.082 5	
TM3	0.147	0.069 6	0.063 2	0.060 7	0.057 9	0.126 7	0.075 0	

Note:

- Above RF exposure measurement was performed considering worst position of isotropic probe.

- Fast Charge mode

4.4.1. Test mode: test result of rotating the probe through various angles

Distance : 15cm surrounding the device and 20cm above the top surface.

- E-field measurement results (Sides of probe)

Frequency [MHz]	E-field Measurement [V/m]					Limits [V/m]
	Probe rotation					
	A	B	C	D	E	
0.118	1.236	1.674	1.793	1.161	1.529	614.00

- H-field measurement results (Sides of probe)

H-field measurement results (Sides of probe)						
Frequency [MHz]	H-field Measurement [A/m]					Limits [A/m]
	Probe rotation					
	A	B	C	D	E	
0.118	0.122	0.054	0.053	0.138	0.121	1.630

- E-field measurement results (Rotation of probe)

E-field measurement results (Rotation of probe)									
Frequency [MHz]	E-field Measurement [V/m]								Limits [V/m]
	Probe rotation								
	A to E	B to E	C to E	D to E	A to B	B to C	C to D	D to A	
0.118	0.859	0.842	0.804	0.774	1.119	1.097	1.171	0.945	614.00

- H-field measurement results (Rotation of probe)

Frequency [MHz]	H-field Measurement [A/m]								Limits [A/m]
	Probe rotation								
	A to E	B to E	C to E	D to E	A to B	B to C	C to D	D to A	
0.118	0.071	0.036	0.036	0.040	0.037	0.036	0.039	0.037	1.630

Note:

- Worst Case: E-field = C-side, H-field = D-side.

4.4.2. Test mode: Test result of EUT's sides about the distance

Distance : 15cm surrounding the device and 20cm above the top surface.

- E-field measurement results

Test Mode	Frequency [MHz]	E-field Measurement [V/m]						Limits [V/m]
		EUT sides						
		A	B	C	D	E	F	
TM1	0.118	0.244 2	0.219 9	0.224 8	0.242 7	1.349 2	0.219 2	614.00
TM2	0.118	0.246 6	0.221 4	0.224 4	0.237 7	1.357 9	0.219 5	
TM3	0.118	0.248 2	0.220 6	0.224 4	0.236 3	1.364 6	0.219 0	

- H-field measurement results

Test Mode	Frequency [MHz]	H-field Measurement [A/m]						Limits [A/m]
		EUT sides						
		A	B	C	D	E	F	
TM1	0.118	0.037 3	0.037 7	0.037 1	0.036 7	0.037 7	0.036 8	1.630
TM2	0.118	0.037 5	0.036 0	0.037 7	0.036 4	0.036 9	0.036 7	
TM3	0.118	0.037 1	0.036 6	0.037 0	0.036 3	0.037 5	0.036 8	

Note:

- Above RF exposure measurement was performed considering worst position of isotropic probe.

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5. Measurement Equipment

Equipment Name	Manufacturer	Model No.	Serial No.	Next Cal. Date
E&H Field Probe	narda	EHP-200A	170WX81015	22.01.29

End of test report

